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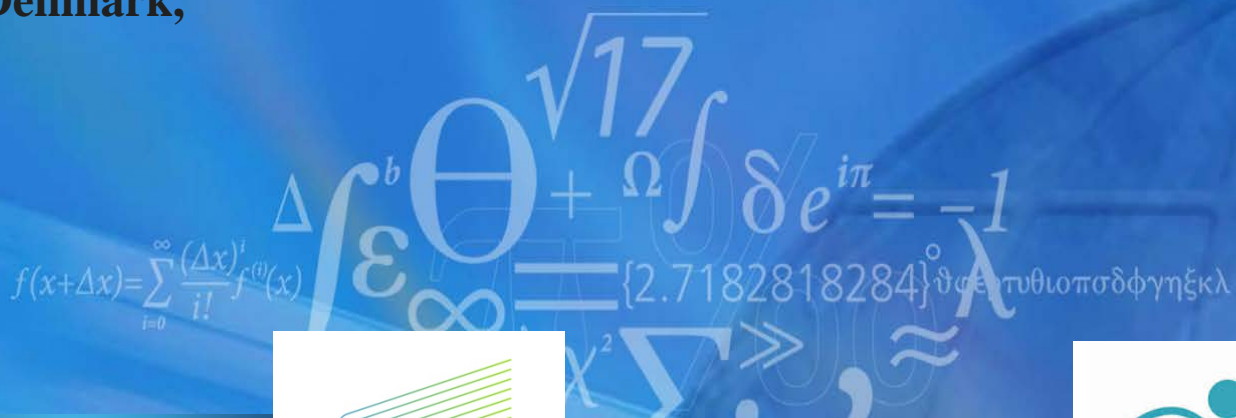
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# Block Copolymer Self-Assembly based nanopattern creation for sub-16 nm device fabrication

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## Why and How ?

- ❖ To continue Moores' law/ statement ...
- ❖ Betterment and strong demand for ICT
- ❖ Top-Down approach( Advanced Lithographic techniques)
- ❖ Bottom-Up approach( Block copolymer self-assembly)

# Diblock copolymer self-assembly

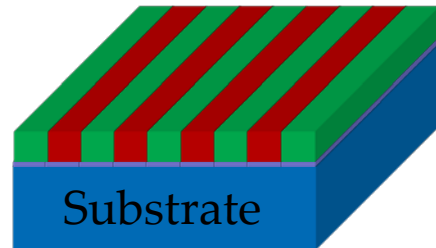
Symmetric Diblock Copolymer



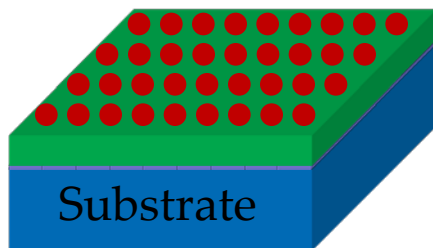
Asymmetric Diblock Copolymer



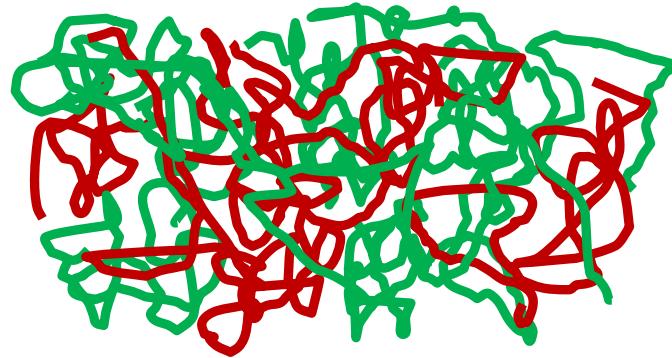
Symmetric Diblock Copolymer



Asymmetric Diblock Copolymer

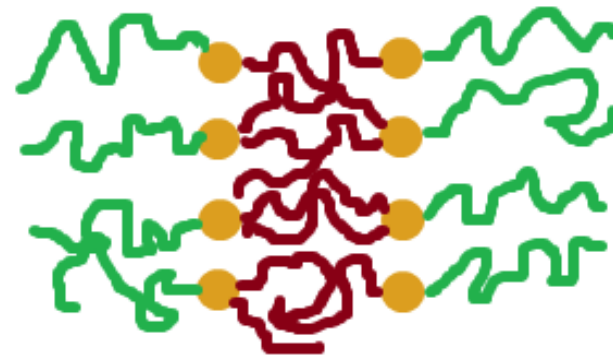


Entangled Polymer Chains



Annealing above  $T_g$

Phase separation after annealing

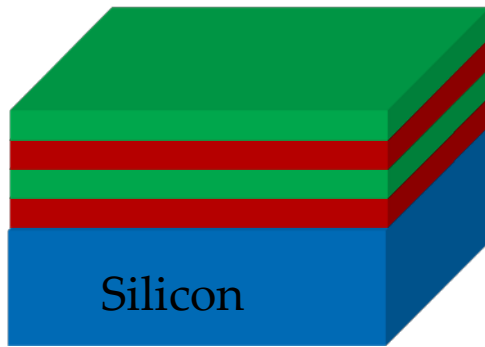
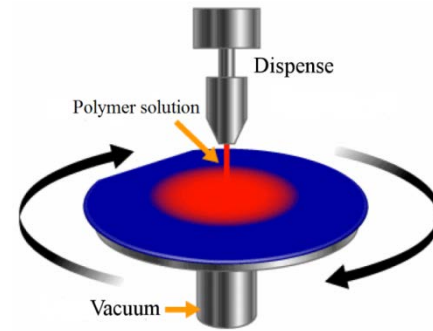


Two BCP systems:

- ❖ PS-*b*-PMMA, PS (polystyrene) - PMMA (polymethylmethacrylate)
- ❖ PS-*b*-PDMS, PS (polystyrene)- PDMS (polydimethylsilixane)

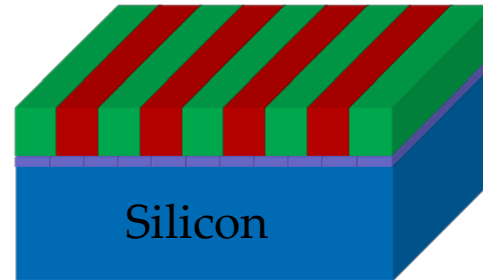
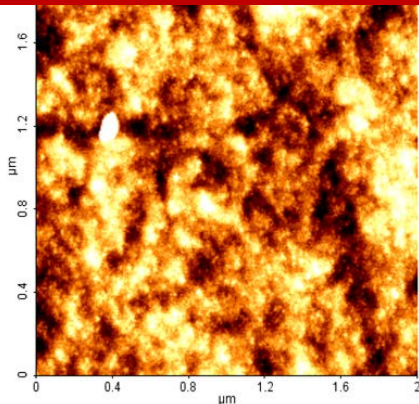
# Preparation and orientation of diblock copolymer thin film

- Spin coating for 30sec with ramp of time 5sec
- Uniform film thickness
- Low surface roughness



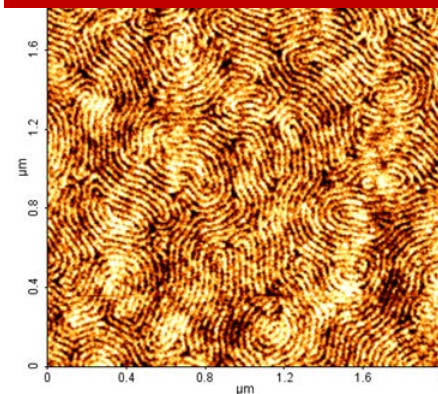
Parallel orientation

PS-b-PMMA(18k-18k)



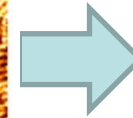
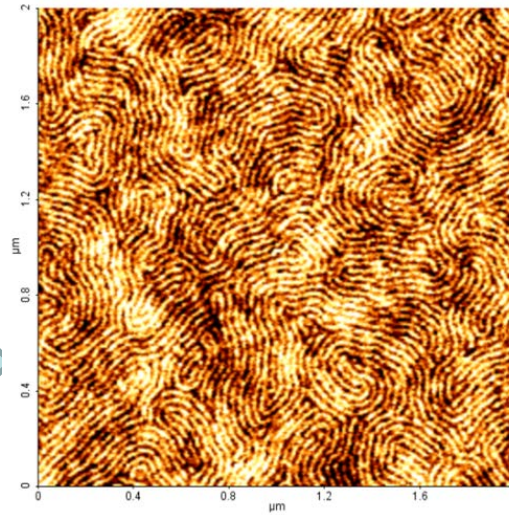
Perpendicular orientation

PS-b-PMMA(18k-18k)

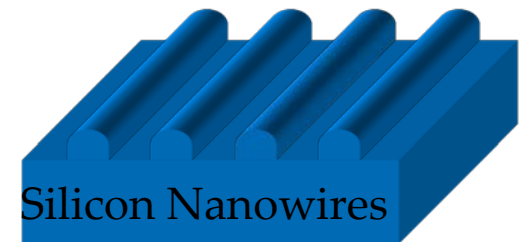
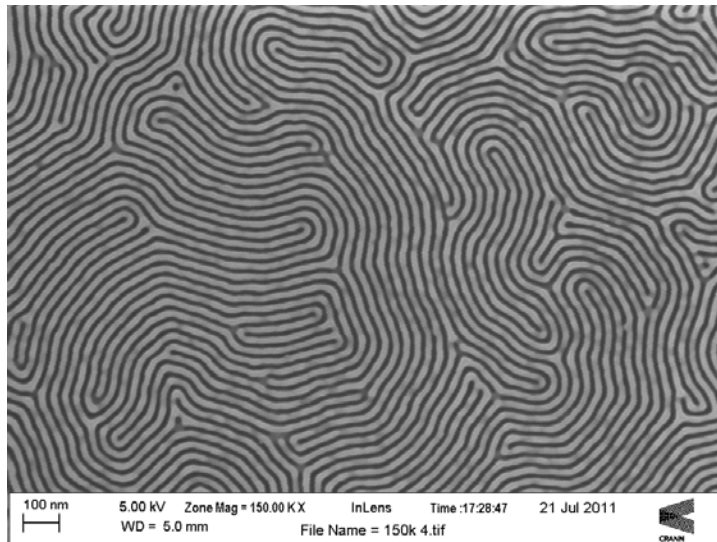
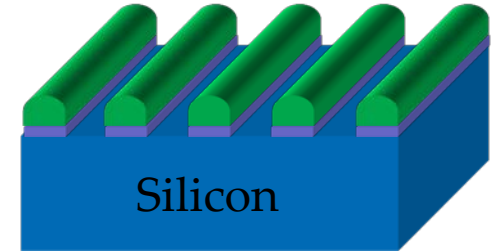


# Nanowire fabrication using PS block as a soft mask

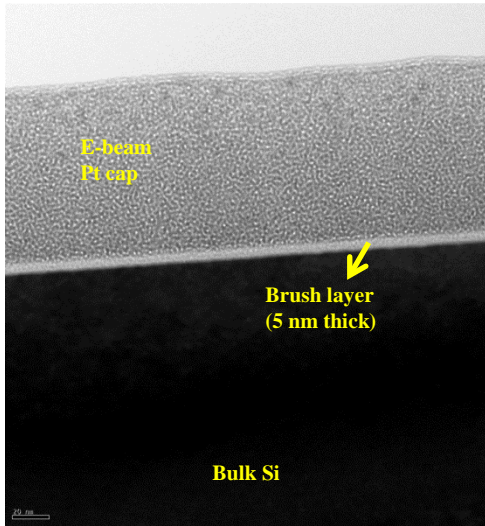
Surface  
Neutralization



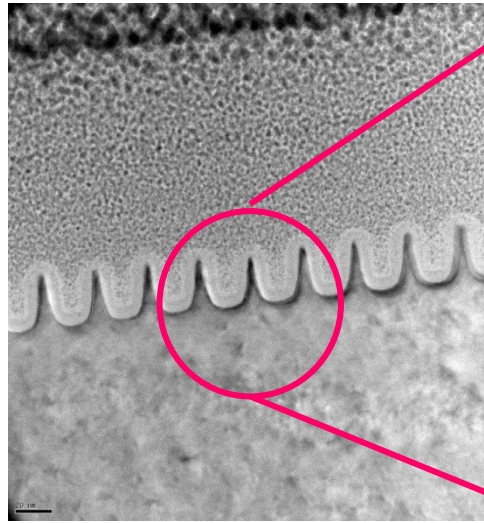
Selective etching of  
PMMA block



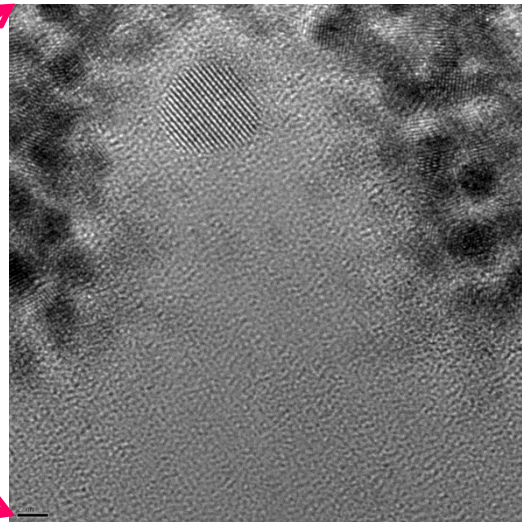
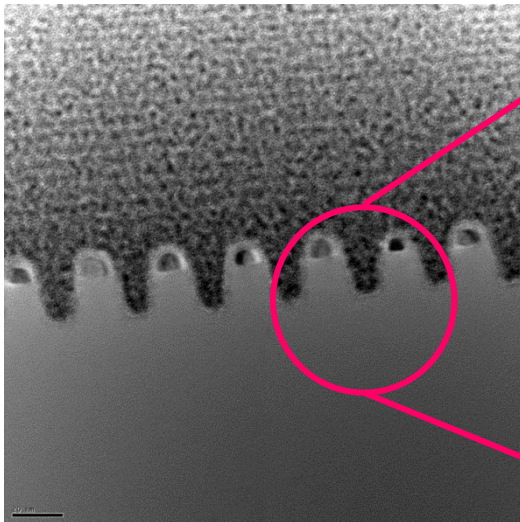
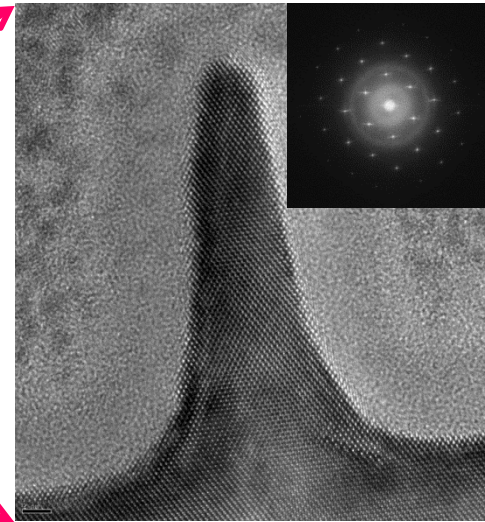
# High resolution TEM images



PS-r-PMMA brush layer



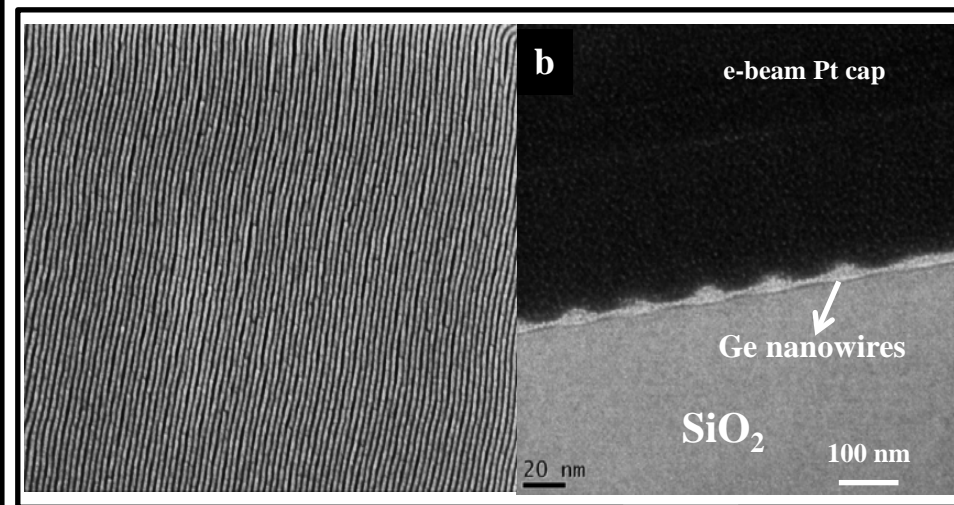
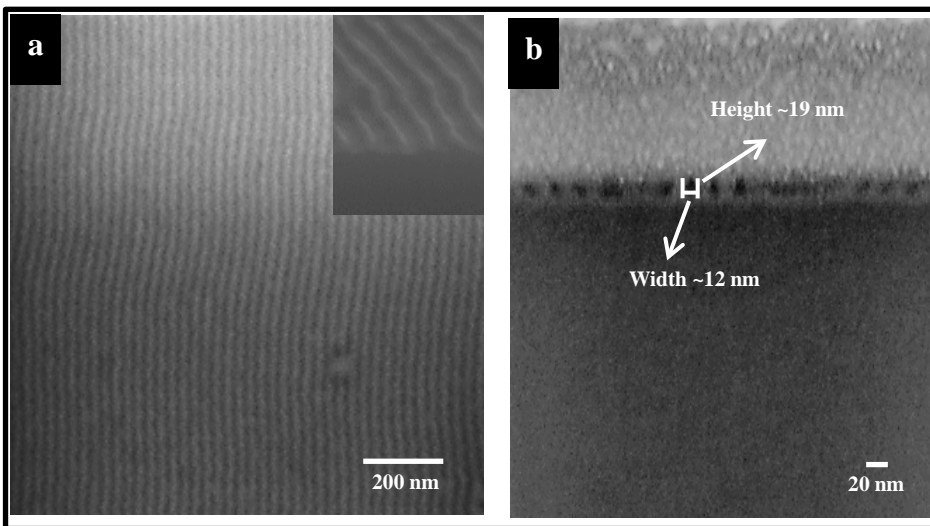
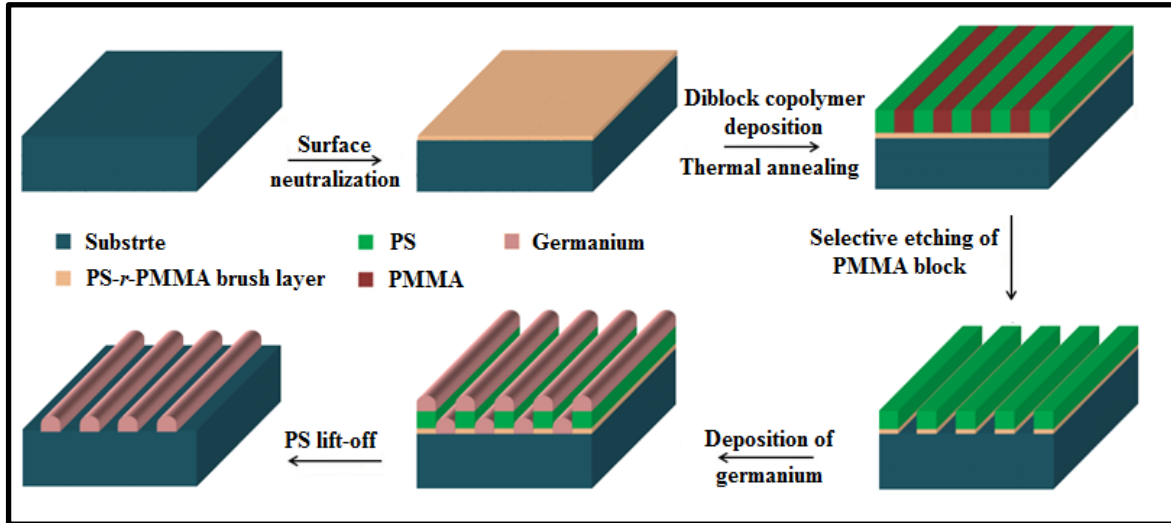
8 nm Silicon nanowires



Si nanowires developed in SOI substrate



# Fabrication of Germanium nanowires

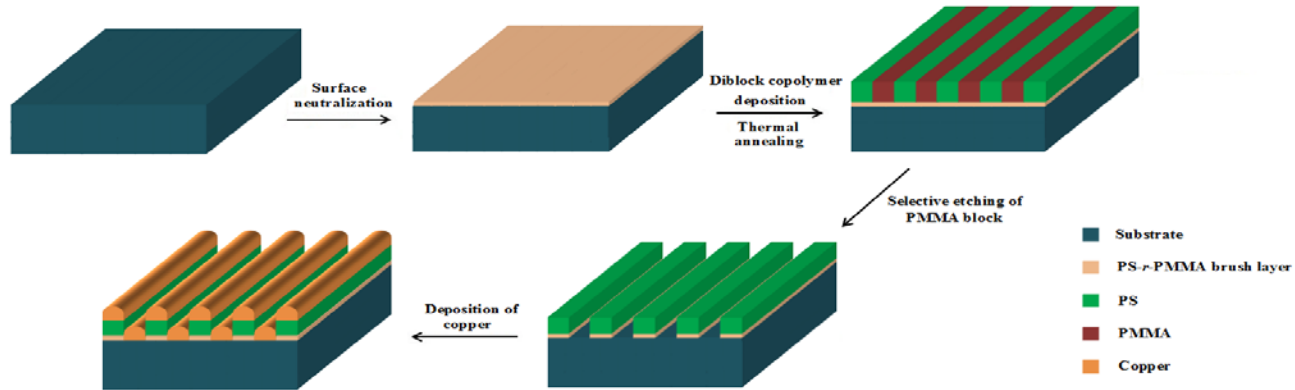


**Figure 1.** (a) Top-down SEM image of the PS template created by a selective etch of the PMMA block. Inset (b) is the cross-section SEM image. (b) FIB cross-section image of PS template.

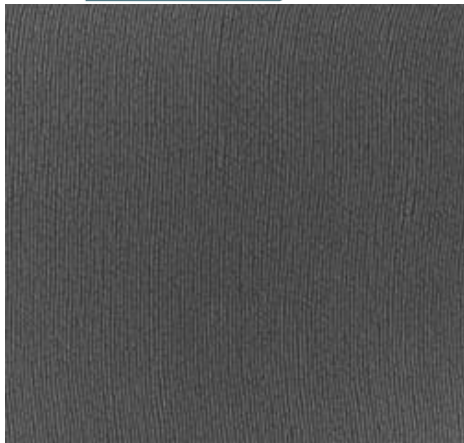
**Figure 2.** (a) Top-down SEM image of GeNWs obtained after PS lift-off (b) Bright-field TEM cross-section image of GeNWs obtained after PS lift-off.

Rasappa, S., D. Borah, et al. (2013). "Fabrication of Germanium Nanowire Arrays by Block Copolymer Lithography." *Science of Advanced Materials* 5: 1-6.

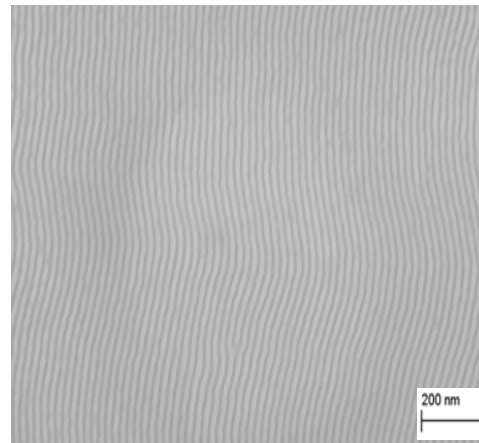
# Fabrication of 3-D Copper nanowires



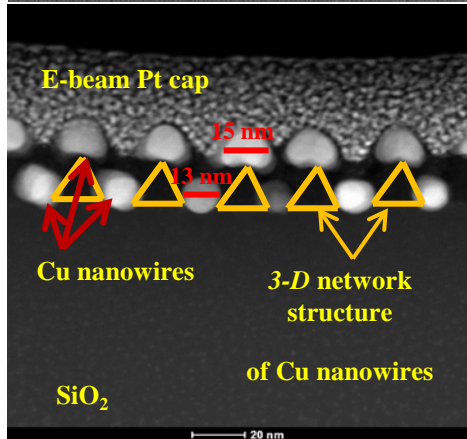
**a**



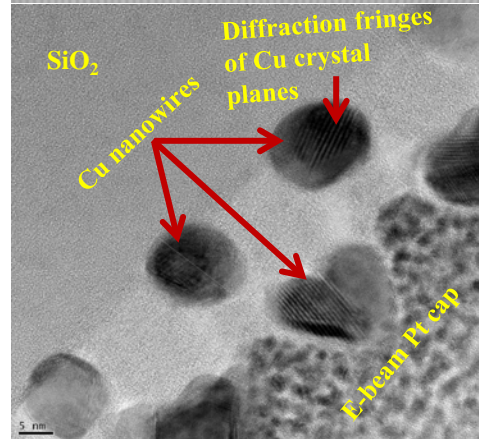
**b**



**c**

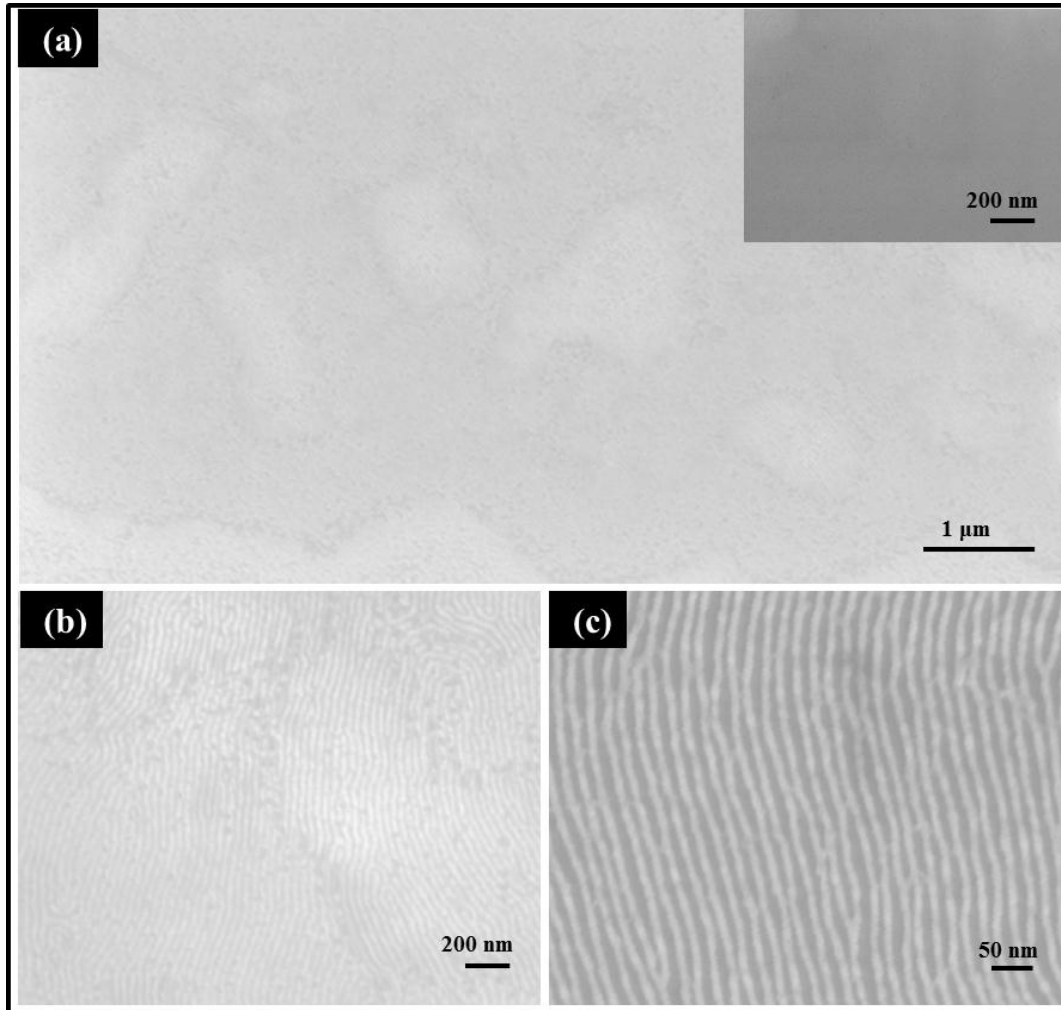


**d**



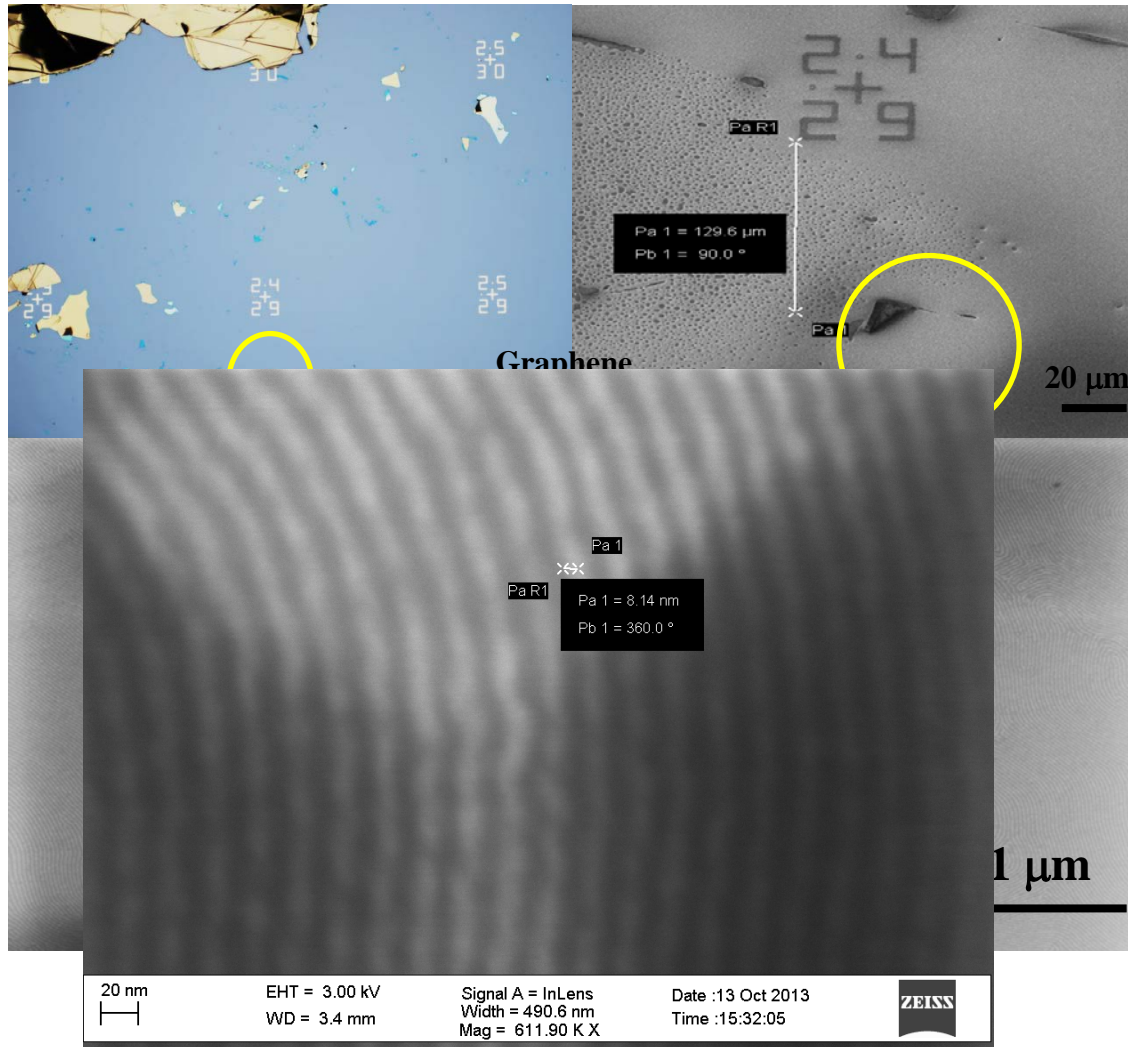
(A) Top-down SEM image of PS template  
 (b) Top down SEM images after copper deposition  
 (c) Dark-field and  
 (d) bright-field TEM cross-section images of Cu nanowires with 3-D geometry.

# PS-*b*-PDMS based sub-16 nm device structures



Top-down SEM images of PS-*b*-PDMS in 4 Inch wafer. (a) Top-down SEM image of PS-*b*-PDMS after PDMS removal and inset shows PS-*b*-PDMS before upper PDMS removal which shows no patterns. (b and c) Low resolution and high resolution of oxidised PDMS cylinders.

PS-b-PDMS on Graphene



## Conclusions:

- ❖ BCP is the potential candidate for low feature size device fabrications.
- ❖ BCP can acts as a template to fabricate cost effective metal and metal-Oxide structures for real device applications.
- ❖ BCP is a breakthrough for Graphene nanopatterning

**Thanks You so much.,..... Looking forward for Expo 2020**